Max Marks: 80

| N.B. | Question No.1 is compulsory Solve any three questions from the remaining questions. Assume suitable data if necessary. | |
|--------|--|--|
| 1. Sol | ve any four of the following. (5 Marks each) | 20 |
| | (a) Define Range and Projection range with respect to ion implantation. | |
| | (b) How to get Si from sand? | S. A. S. |
| | (c) State technological problem during the application of local oxidation. | |
| | (d) Explain RCA wafer cleaning method | |
| | (e) Explain SOI fabrication using bonded SOI and smart cut. | |
| 2. | (a) Explain different defects in crystal. | 10 |
| | (b) Explain Liquid phase epitaxy method with neat diagram. | 10 |
| 3. | (a) State difference between LPCVD, APCVD, PECVD. | 10 |
| | (b) Explain nature of diffusion system and State diffusion equation. | 10 |
| 4. | (a) Enlist the steps of fabrication of CMOS inverter using twin tub process along with ver cross-sectional view. | tical 10 |
| | (b) State need of λ (lambda) based design rules and draw layout of CMOS based 2 input N gate. | NAND 10 |
| 5. | (a) Explain ion implantation system and state need of annealing. | 10 |
| | (b)Explain measurement techniques of resistivity, conductivity and mobility | 10 |
| 6. | Write short note on any four method | 20 |
| | (a) Multi-gate MOSFET physics | |
| | (b) MESFET fabrication | |
| | (c) Application of carbon nano tube. | |
| | (d) Electronic package reliability. | |
| | (e) Comparison of Pin through hole and SMT packaging technique. | |
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Time: 3 Hours